CONTROL OF SEMICONDUCTOR AMI PRS NAME: Sergey A. Velichko et al. SERIAL NO.: 09/834,751 AMETRIC TESTING TITLE: CONCURR INVENTORS NAME: 1/11 FIG. 1 (PRIOR ART) PREPARE AND INITIALIZE INSTRUMENTATION DE-INITIALIZE INSTRUMENTATION PERFORM DATA ANALYSES 105 ~ PERFORM TESTS PREPARE AND INITIALIZE DATA COLLECTIONS 101~ MOVE WAFER TO TEST PINS 104 ~ LOAD TESTS 108 ~ SAVE DATA TIME

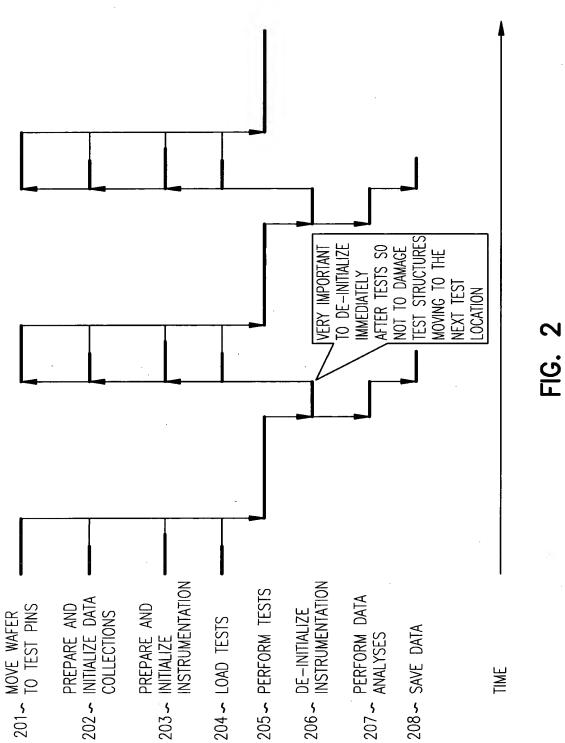
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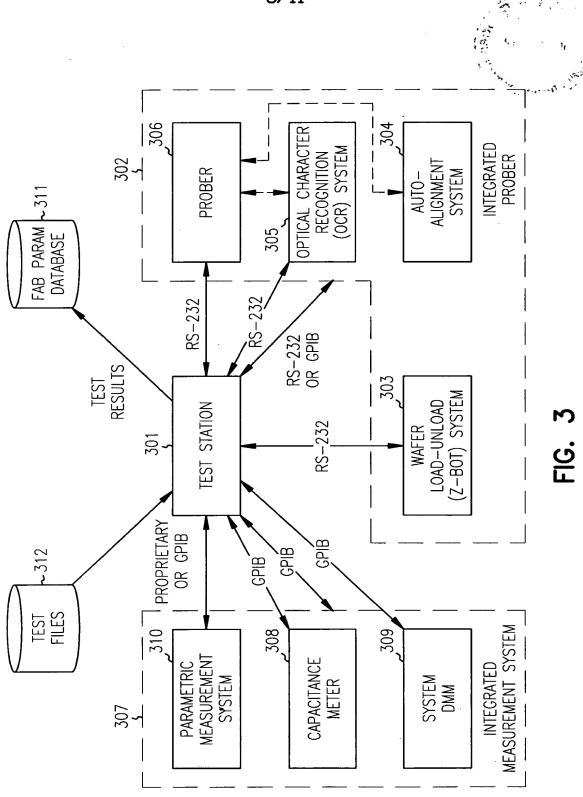


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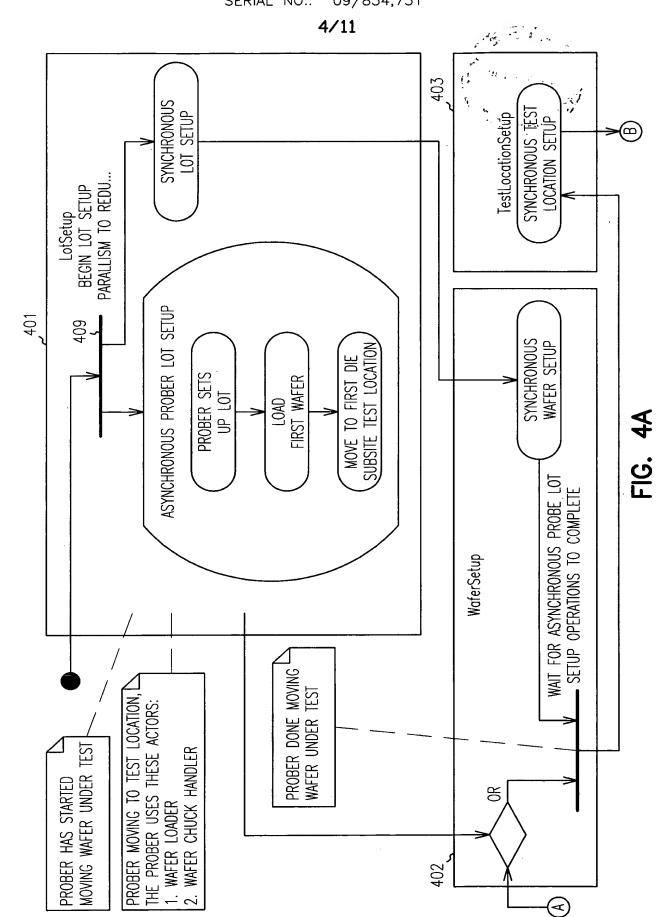
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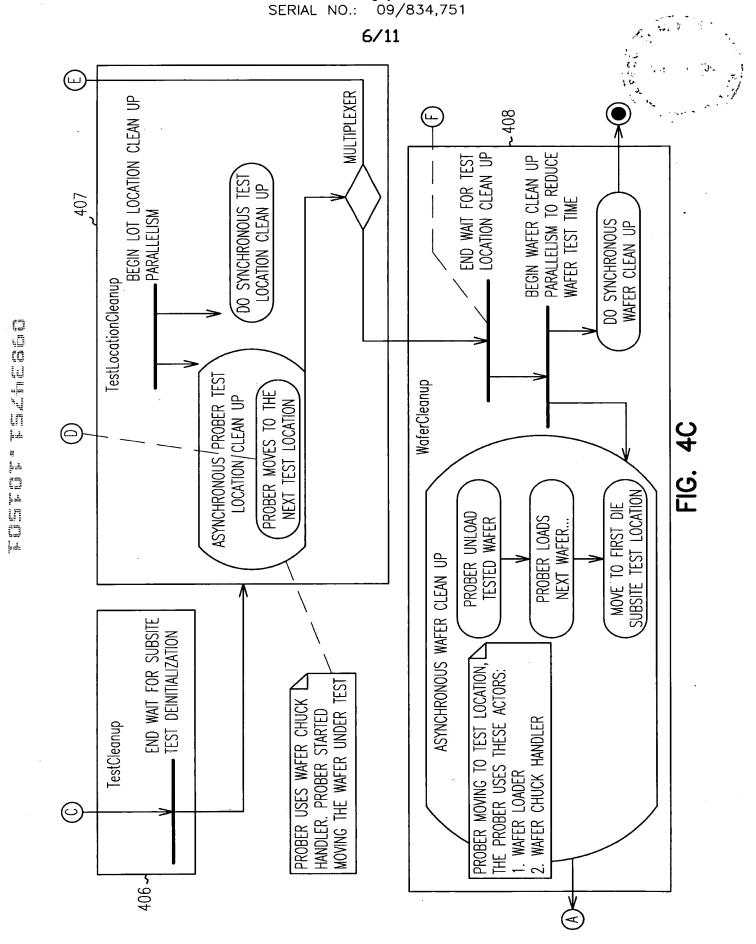
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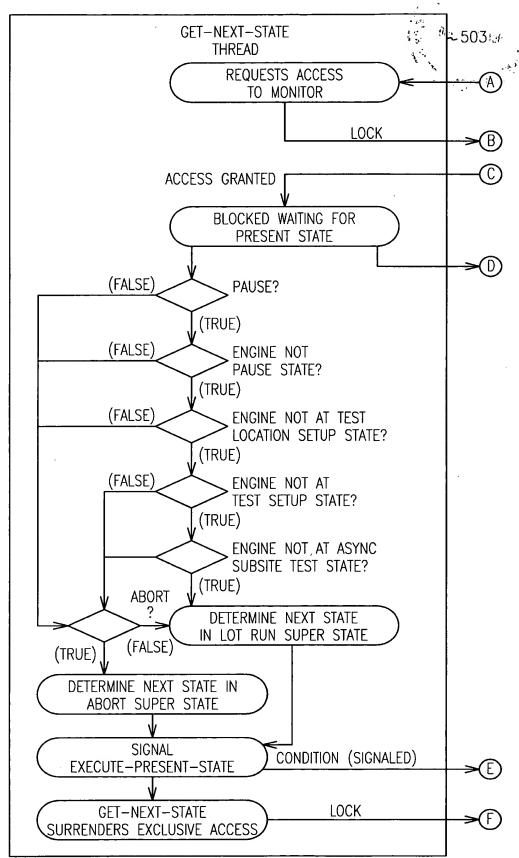


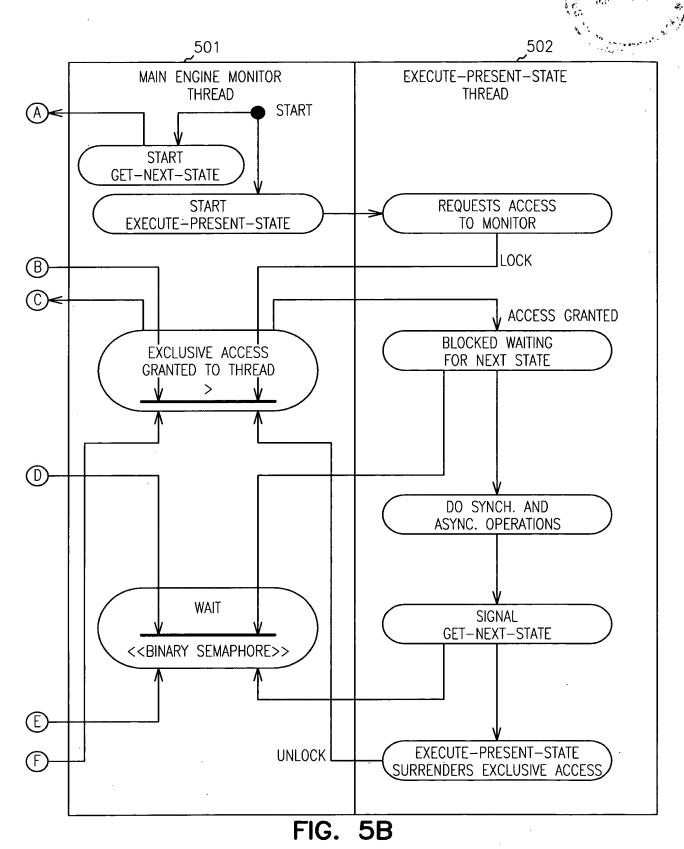
FIG. 5A

CONTROL OF SEMICONDUCTOR

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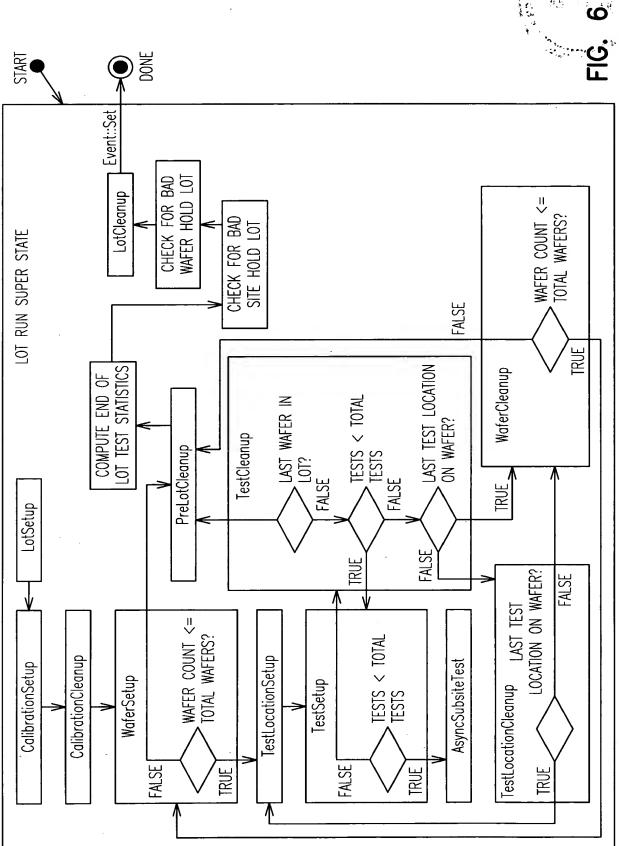
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SERIAL NO.: 09/834,751

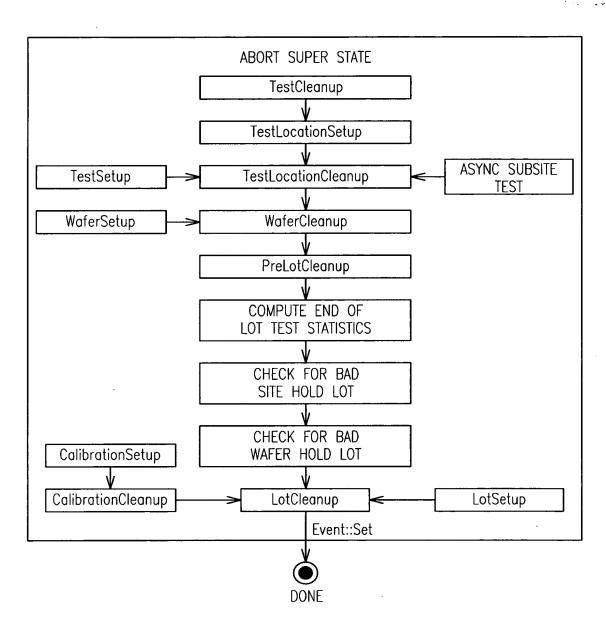


FIG. 7

